

Notice of References Cited	Application/Control No. 10/001,709	Applicant(s)/Patent Under Reexamination SAIKI ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0180149	09-2004	Shibue et al.	428/001.1
	B	US-2004/0246581	12-2004	Miyatake et al.	359/495
	C	US-2002/0015807	02-2002	Sugino et al.	428/1.31
	D	US-6,600,529	07-2003	Kusumoto et al.	349/96
	E	US-6,661,482	12-2003	Hara, Kazutaka	349/96
	F	US-2003/0053011	03-2003	Mori, Eiichi	349/96
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 8-271934	10-1996	Japan	Tanaka	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.